

**Search Notes**

Application/Control No.

10/617,076

Examiner

Sun J. Lin

Applicant(s)/Patent under  
Reexamination

TANAKA, GENICHI

Art Unit

2825

**SEARCHED**

Class	Subclass	Date	Examiner
716	6	3/3/2006	JSL
716	7	3/3/2006	JSL
716	4	3/3/2006	JSL
716	5	3/3/2006	JSL

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST [USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB]	3/3/2006	JSL
EAST [USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB]	3/13/2006	JSL